Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/511,878	HUNT ET AL.	
Examiner	Art Unit	
Ardith F. Hertzon	1754	•

	SEARCHED				
Class	Subclass	Date	Examiner		
588	314, 406, 900	6/13/2005	AEH		
422	127, 128	6/13/2005	AEH		
422	900	6/13/2005	AEH		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
1	•				

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
file for "parent" application, PCT/CA / downloaded for review, via www.eponline.org	6/1/2005	AEH
eDAN inventor search	6/8/2005	AEH
reviewed provisional app 60/374,512 (including check for 112 support of all claims)	6/9/2005	AEH
STIC search of NPL+ databases (see attached printout)	6/10/2005	AEH
EAST searches of USPAT/USPGPUB; USOCR &/or EPO/JPO/DERWENT/IBM_TDB databases (see attached strategy)	10,13	AEH
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